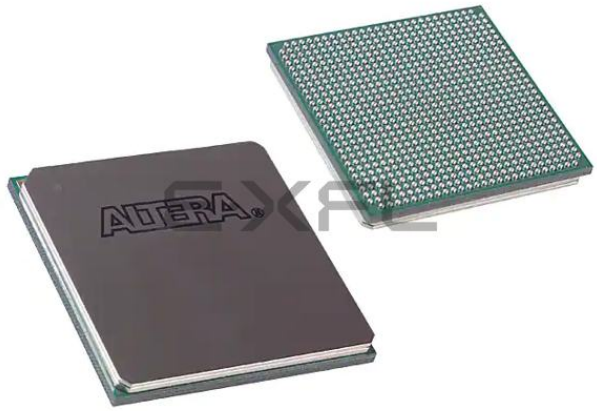

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	3022
Number of Logic Elements/Cells	60440
Total RAM Bits	2544192
Number of I/O	364
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	780-BBGA
Supplier Device Package	780-FBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2sgx60df780i4

There are up to 20 transceiver channels available on a single Stratix II GX device. Table 2–1 shows the number of transceiver channels and their serial bandwidth for each Stratix II GX device.

Table 2–1. Stratix II GX Transceiver Channels

Device	Number of Transceiver Channels	Serial Bandwidth (Full Duplex)
EP2SGX30C	4	51 Gbps
EP2SGX60C	4	51 Gbps
EP2SGX30D	8	102 Gbps
EP2SGX60D	8	102 Gbps
EP2SGX60E	12	153 Gbps
EP2SGX90E	12	153 Gbps
EP2SGX90F	16	204 Gbps
EP2SGX130G	20	255 Gbps

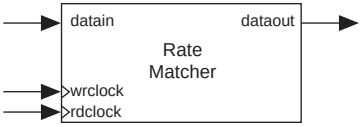
Figure 2–2 shows the elements of the transceiver block, including the four transceiver channels, supporting logic, and I/O buffers. Each transceiver channel consists of a receiver and transmitter. The supporting logic contains two transmitter PLLs to generate the high-speed clock(s) used by the four transmitters within that block. Each of the four transmitter channels has its own individual clock divider. The four receiver PLLs within each transceiver block generate four recovered clocks. The transceiver channels can be configured in one of the following functional modes:

- PCI Express (PIPE)
- OIF CEI PHY Interface
- SONET/SDH
- Gigabit Ethernet (GIGE)
- XAUI
- Basic (600 Mbps to 3.125 Gbps single-width mode and 1 Gbps to 6.375 Gbps double-width mode)
- SDI (HD, 3G)
- CPRI (614 Mbps, 1228 Mbps, 2456 Mbps)
- Serial RapidIO (1.25 Gbps, 2.5 Gbps, 3.125 Gbps)

Rate Matcher

Rate matcher is available in Basic, PCI Express, XAUI, and GIGE modes and consists of a 20-word deep FIFO buffer and a FIFO controller. Figure 2–20 shows the implementation of the rate matcher in the Stratix II GX device.

Figure 2–20. Rate Matcher



In a multi-crystal environment, the rate matcher compensates for up to a ± 300-PPM difference between the source and receiver clocks. Table 2–8 shows the standards supported and the PPM for the rate matcher tolerance.

Table 2–8. Rate Matcher PPM Support *Note (1)*

Standard	PPM
XAUI	± 100
PCI Express (PIPE)	± 300
GIGE	± 100
Basic Double-Width	± 300

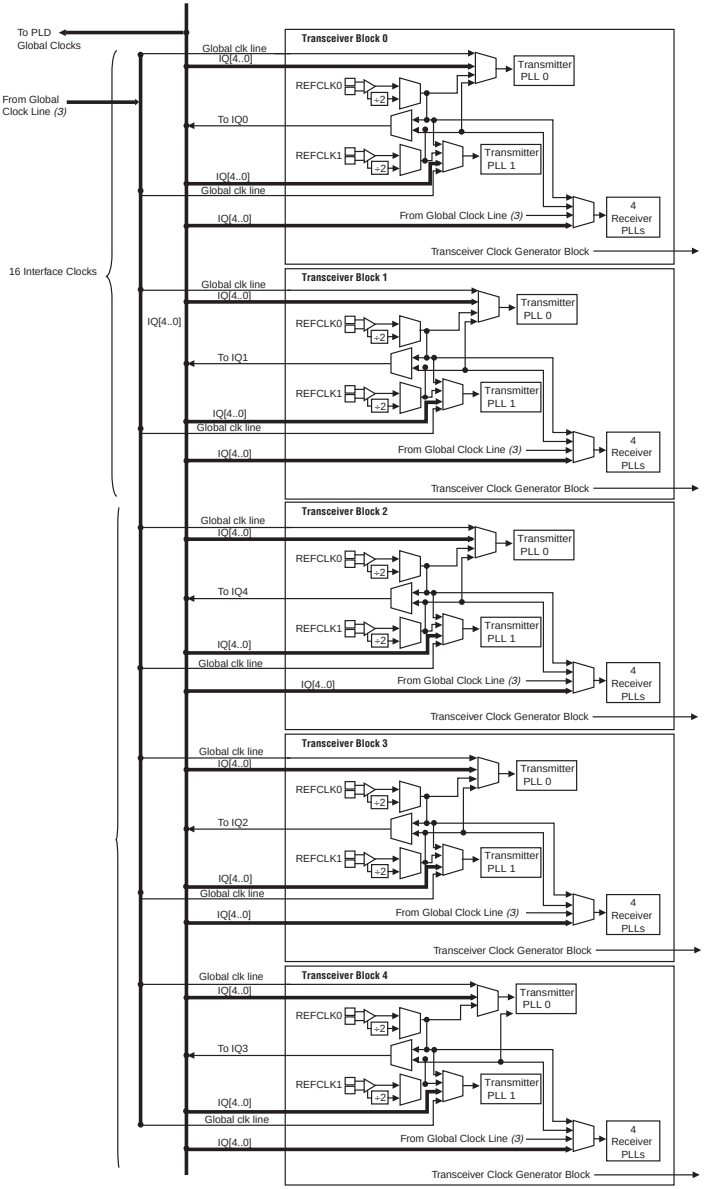
Note to Table 2–8:

(1) Refer to the *Stratix II GX Transceiver User Guide* for the Altera®-defined scheme.

Basic Mode

In Basic mode, you can program the skip and control pattern for rate matching. In single-width Basic mode, there is no restriction on the deletion of a skip character in a cluster. The rate matcher deletes the skip characters as long as they are available. For insertion, the rate matcher inserts skip characters such that the number of skip characters at the output of rate matcher does not exceed five. In double-width mode, the rate matcher deletes skip character when they appear as pairs in the upper and lower bytes. There are no restrictions on the number of skip characters that are deleted. The rate matcher inserts skip characters as pairs.

Figure 2–29. EP2SGX130 Device Inter-Transceiver and Global Clock Connections



Notes to Figure 2–29:

(1) There are two transmitter PLLs in each transceiver block.
(2) There are four receiver PLLs in each transceiver block.
(3) The Global Clock line must be driven by an input pin.

IOE clocks have row and column block regions that are clocked by 8 I/O clock signals chosen from the 24 quadrant clock resources. Figures 2–65 and 2–66 show the quadrant relationship to the I/O clock regions.

Figure 2–65. EP2SGX30 Device I/O Clock Groups

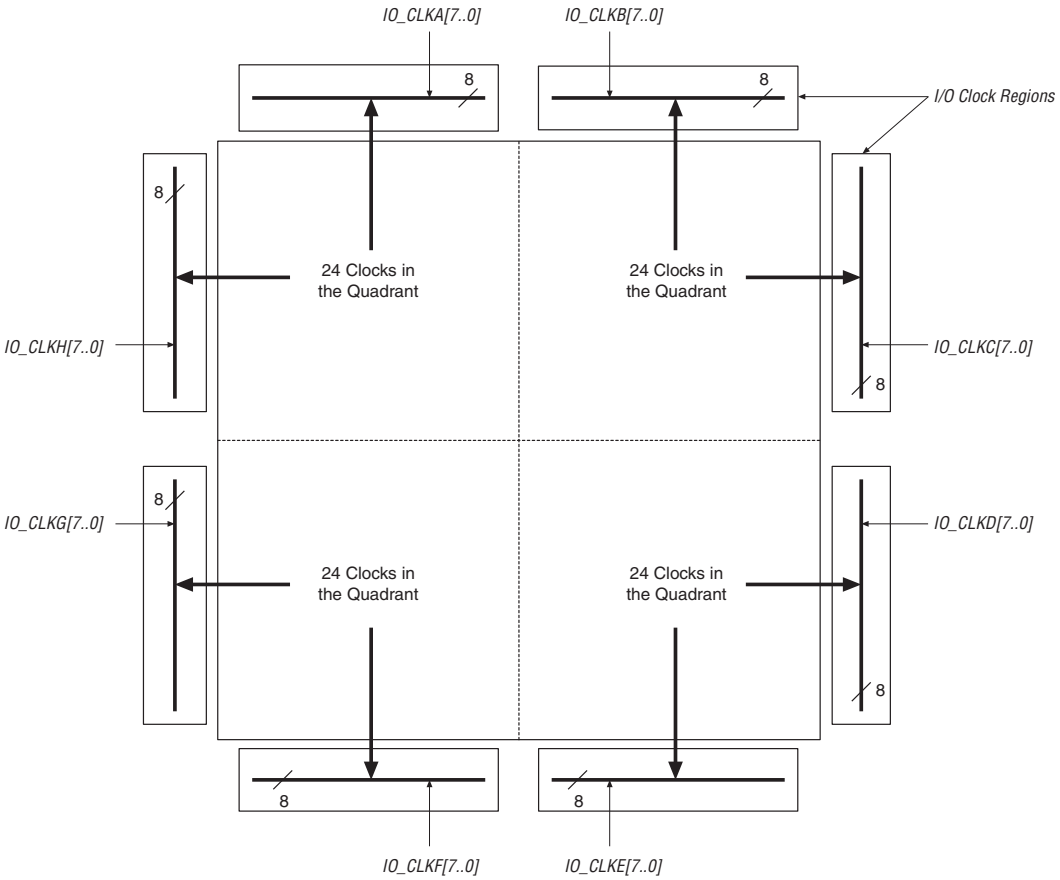
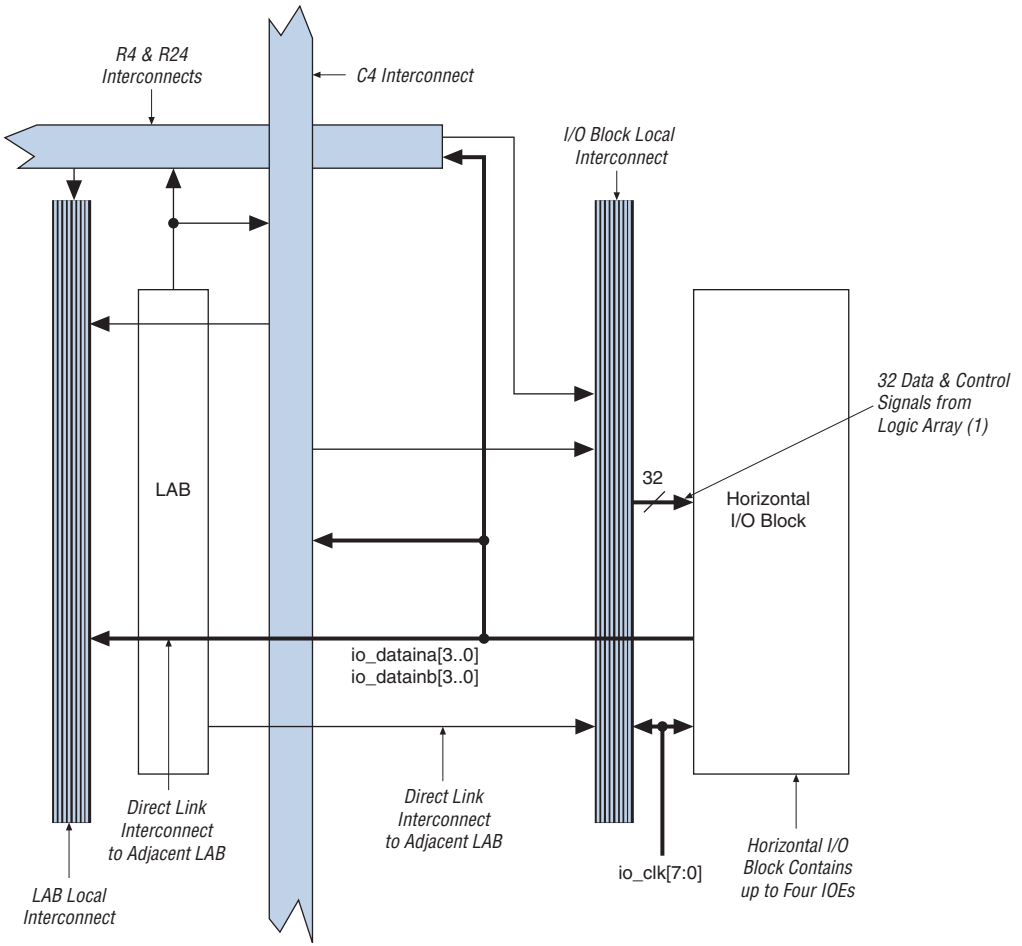


Figure 2–77 shows how a row I/O block connects to the logic array.

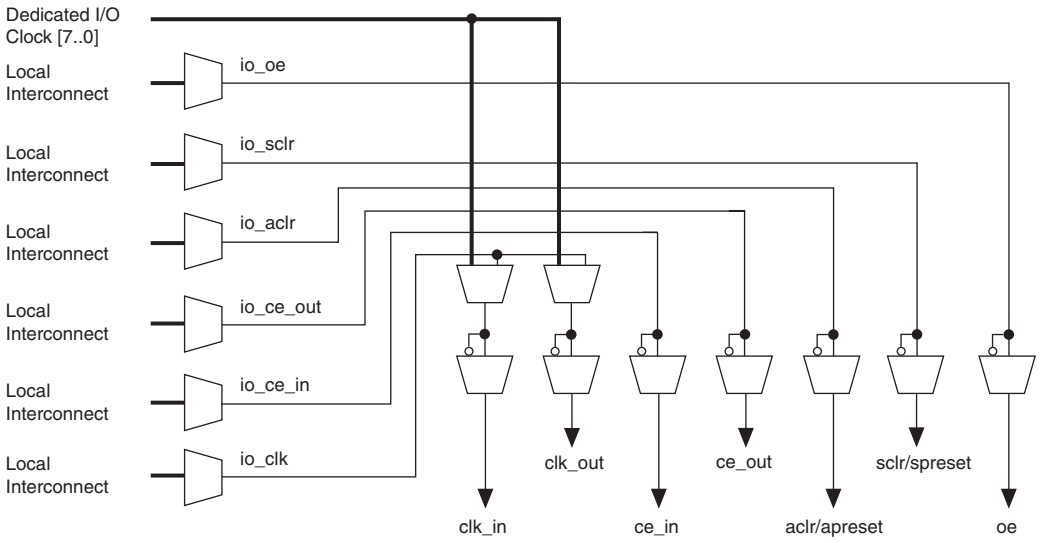
Figure 2–77. Row I/O Block Connection to the Interconnect



Note to Figure 2–77:

(1) The 32 data and control signals consist of eight data out lines: four lines each for DDR applications `io_dataouta[3..0]` and `io_dataoutb[3..0]`, four output enables `io_oe[3..0]`, four input clock enables `io_ce_in[3..0]`, four output clock enables `io_ce_out[3..0]`, four clocks `io_clk[3..0]`, four asynchronous clear and preset signals `io_aclr/apreset[3..0]`, and four synchronous clear and preset signals `io_sclr/spreset[3..0]`.

Figure 2–80. Control Signal Selection per IOE *Note (1)*



Note to Figure 2–80:

(1) Control signals `ce_in`, `ce_out`, `aclr/apreset`, `sclr/spreset`, and `oe` can be global signals even though their control selection multiplexers are not directly fed by the `ioe_clk[7..0]` signals. The `ioe_clk` signals can drive the I/O local interconnect, which then drives the control selection multiplexers.

In normal bidirectional operation, you can use the input register for input data requiring fast setup times. The input register can have its own clock input and clock enable separate from the OE and output registers. The output register can be used for data requiring fast clock-to-output performance. You can use the OE register for fast clock-to-output enable timing. The OE and output register share the same clock source and the same clock enable source from local interconnect in the associated LAB, dedicated I/O clocks, and the column and row interconnects. Figure 2–81 shows the IOE in bidirectional configuration.

Table 2–37. Supported TDO/TDI Voltage Combinations (Part 2 of 2)

Device	TDI Input Buffer Power	Stratix II GX TDO V_{CCIO} Voltage Level in I/O Bank 4				
		V_{CCIO} = 3.3 V	V_{CCIO} = 2.5 V	V_{CCIO} = 1.8 V	V_{CCIO} = 1.5 V	V_{CCIO} = 1.2 V
Non-Stratix II GX	VCC = 3.3 V	✓ (1)	✓ (2)	✓ (3)	Level shifter required	Level shifter required
	VCC = 2.5 V	✓ (1), (4)	✓ (2)	✓ (3)	Level shifter required	Level shifter required
	VCC = 1.8 V	✓ (1), (4)	✓ (2), (5)	✓	Level shifter required	Level shifter required
	VCC = 1.5 V	✓ (1), (4)	✓ (2), (5)	✓ (6)	✓	✓

Notes to Table 2–37:

(1) The TDO output buffer meets V_{OH} (MIN) = 2.4 V.
(2) The TDO output buffer meets V_{OH} (MIN) = 2.0 V.
(3) An external 250-Ω pull-up resistor is not required, but recommended if signal levels on the board are not optimal.
(4) Input buffer must be 3.3-V tolerant.
(5) Input buffer must be 2.5-V tolerant.
(6) Input buffer must be 1.8-V tolerant.

High-Speed Differential I/O with DPA Support

Stratix II GX devices contain dedicated circuitry for supporting differential standards at speeds up to 1 Gbps. The LVDS differential I/O standards are supported in the Stratix II GX device. In addition, the LVPECL I/O standard is supported on input and output clock pins on the top and bottom I/O banks.

The high-speed differential I/O circuitry supports the following high-speed I/O interconnect standards and applications:

- SPI-4 Phase 2 (POS-PHY Level 4)
- SFI-4
- Parallel RapidIO standard

There are two dedicated high-speed PLLs in the EP2SGX30 device and four dedicated high-speed PLLs in the EP2SGX60, EP2SGX90, and EP2SGX130 devices to multiply reference clocks and drive high-speed differential SERDES channels.

Tables 2–38 through 2–41 show the number of channels that each Fast PLL can clock in each of the Stratix II GX devices. In Tables 2–38 through 2–41, the first row for each transmitter or receiver provides the number of channels driven directly by the PLL. The second row below it shows the maximum channels a Fast PLL can drive if cross bank channels are used from the adjacent center Fast PLL. For example, in the 780-pin FineLine BGA EP2SGX30 device, PLL 1 can drive a maximum of

Table 2–41. EP2SGX130 Device Differential Channels *Note (1)*

Package	Transmitter/Receiver	Total Channels	Center Fast PLLs		Corner Fast PLLs	
			PLL1	PLL2	PLL7	PLL8
1508-pin FineLine BGA	Transmitter	71	37	41	37	41
	Receiver	73	37	41	37	41

Note to Tables 2–38 through 2–41:
(1) The total number of receiver channels includes the four non-dedicated clock channels that can be optionally used as data channels.

Therefore, the total number of channels is not the addition of the number of channels accessible by PLLs 1 and 2 with the number of channels accessible by PLLs 7 and 8.

Dedicated Circuitry with DPA Support

Stratix II GX devices support source-synchronous interfacing with LVDS signaling at up to 1 Gbps. Stratix II GX devices can transmit or receive serial channels along with a low-speed or high-speed clock.

The receiving device PLL multiplies the clock by an integer factor W = 1 through 32. The SERDES factor J determines the parallel data width to deserialize from receivers or to serialize for transmitters. The SERDES factor J can be set to 4, 5, 6, 7, 8, 9, or 10 and does not have to equal the PLL clock-multiplication W value. A design using the dynamic phase aligner also supports all of these J factor values. For a J factor of 1, the Stratix II GX device bypasses the SERDES block. For a J factor of 2, the Stratix II GX device bypasses the SERDES block, and the DDR input and output registers are used in the IOE. Figure 2–88 shows the block diagram of the Stratix II GX transmitter channel.

Table 2–42. Document Revision History (Part 6 of 6)

Date and Document Version	Changes Made	Summary of Changes
Previous Chapter 03 changes: December 2005 v1.1	Updated Figure 3–56.	
Previous Chapter 03 changes: October 2005 v1.0	Added chapter to the *Stratix II GX Device Handbook*.	

memory, and transmit this compressed bitstream to Stratix II GX FPGAs. During configuration, the Stratix II GX FPGA decompresses the bitstream in real time and programs its SRAM cells. Stratix II GX FPGAs support decompression in the FPP (when using a MAX II device or microprocessor and flash memory), AS, and PS configuration schemes. Decompression is not supported in the PPA configuration scheme nor in JTAG-based configuration.

Remote System Upgrades

Shortened design cycles, evolving standards, and system deployments in remote locations are difficult challenges faced by system designers. Stratix II GX devices can help effectively deal with these challenges with their inherent re programmability and dedicated circuitry to perform remote system updates. Remote system updates help deliver feature enhancements and bug fixes without costly recalls, reducing time to market, and extending product life.

Stratix II GX FPGAs feature dedicated remote system upgrade circuitry to facilitate remote system updates. Soft logic (Nios processor or user logic) implemented in the Stratix II GX device can download a new configuration image from a remote location, store it in configuration memory, and direct the dedicated remote system upgrade circuitry to initiate a reconfiguration cycle. The dedicated circuitry performs error detection during and after the configuration process, recovers from any error condition by reverting back to a safe configuration image, and provides error status information. This dedicated remote system upgrade circuitry avoids system downtime and is the critical component for successful remote system upgrades.

Remote system configuration is supported in the following Stratix II GX configuration schemes: FPP, AS, PS, and PPA. Remote system configuration can also be implemented in conjunction with Stratix II GX features such as real-time decompression of configuration data and design security using AES for secure and efficient field upgrades.

Refer to the *Remote System Upgrades with Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II GX Device Handbook* for more information about remote configuration in Stratix II GX devices.

Configuring Stratix II GX FPGAs with JRunner

The JRunner™ software driver configures Altera FPGAs, including Stratix II GX FPGAs, through the ByteBlaster II or ByteBlasterMV cables in JTAG mode. The programming input file supported is in Raw Binary File (**.rbf**) format. JRunner also requires a Chain Description File (**.cdf**)

Table 4–19. Stratix II GX Transceiver Block AC Specification Notes (1), (2), (3) (Part 7 of 19)

Symbol/ Description	Conditions	-3 Speed Commercial Speed Grade			-4 Speed Commercial and Industrial Speed Grade			-5 Speed Commercial Speed Grade			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Sinusoidal Jitter Tolerance (peak-to-peak)	Jitter Frequency = 22.1 KHz Data Rate = 1.25, 2.5, 3.125 Gbps REFCLK = 125 MHz Pattern = CJPAT Equalizer Setting = 0 for 1.25 Gbps Equalizer Setting = 6 for 2.5 Gbps Equalizer Setting = 6 for 3.125 Gbps		> 8.5			> 8.5			> 8.5		UI
	Jitter Frequency = 1.875 MHz Data Rate = 1.25, 2.5, 3.125 Gbps REFCLK = 125 MHz Pattern = CJPAT Equalizer Setting = 0 for 1.25 Gbps Equalizer Setting = 6 for 2.5 Gbps Equalizer Setting = 6 for 3.125 Gbps		> 0.1			> 0.1			> 0.1		UI
	Jitter Frequency = 20 MHz Data Rate = 1.25, 2.5, 3.125 Gbps REFCLK = 125 MHz Pattern = CJPAT Equalizer Setting = 0 for 1.25 Gbps Equalizer Setting = 6 for 2.5 Gbps Equalizer Setting = 6 for 3.125 Gbps		> 0.1			> 0.1			> 0.1		UI

Table 4–19. Stratix II GX Transceiver Block AC Specification Notes (1), (2), (3) (Part 9 of 19)

Symbol/ Description	Conditions	-3 Speed Commercial Speed Grade			-4 Speed Commercial and Industrial Speed Grade			-5 Speed Commercial Speed Grade			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
HiGig Receiver Jitter Tolerance *(13)*											
Deterministic Jitter Tolerance (peak-to-peak)	Data Rate = 3.75 Gbps REFCLK = 187.5 MHz Pattern = CJPAT No Equalization DC Gain = 3 dB		> 0.37			-			-		UI
Combined Deterministic and Random Jitter Tolerance (peak-to-peak)	Data Rate = 3.75 Gbps REFCLK = 187.5 MHz Pattern = CJPAT No Equalization DC Gain = 3 dB		> 0.65			-			-		UI
	Jitter Frequency = 22.1 KHz Data Rate = 3.75 Gbps REFCLK = 187.5 MHz Pattern = CJPAT No Equalization DC Gain = 3 dB		> 8.5			-			-		UI

Table 4–39. SSTL-2 Class II Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{IH} (DC)	High-level DC input voltage		V_{REF} + 0.18		V_{CCIO} + 0.3	V
V_{IL} (DC)	Low-level DC input voltage		–0.3		V_{REF} – 0.18	V
V_{IH} (AC)	High-level AC input voltage		V_{REF} + 0.35			V
V_{IL} (AC)	Low-level AC input voltage				V_{REF} – 0.35	V
V_{OH}	High-level output voltage	I_{OH} = –16.4 mA *(1)*	V_{TT} + 0.76			V
V_{OL}	Low-level output voltage	I_{OL} = 16.4 mA *(1)*			V_{TT} – 0.76	V

Note to Table 4–39:

(1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II GX Architecture* chapter in volume 1 of the *Stratix II GX Device Handbook*.

Table 4–40. SSTL-2 Class I and II Differential Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		2.375	2.5	2.625	V
V_{SWING} (DC)	DC differential input voltage		0.36			V
V_X (AC)	AC differential input cross point voltage		(V_{CCIO}/2) – 0.2		(V_{CCIO}/2) + 0.2	V
V_{SWING} (AC)	AC differential input voltage		0.7			V
V_{ISO}	Input clock signal offset voltage			0.5 V_{CCIO}		V
ΔV_{ISO}	Input clock signal offset voltage variation			200		mV
V_{OX} (AC)	AC differential output cross point voltage		(V_{CCIO}/2) – 0.2		(V_{CCIO}/2) + 0.2	V

Table 4–41. 1.2-V HSTL Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		1.14	1.2	1.26	V
V_{REF}	Reference voltage		0.48 V_{CCIO}	0.5 V_{CCIO}	0.52 V_{CCIO}	V
V_{IH} (DC)	High-level DC input voltage		V_{REF} + 0.08		V_{CCIO} + 0.15	V
V_{IL} (DC)	Low-level DC input voltage		–0.15		V_{REF} – 0.08	V
V_{IH} (AC)	High-level AC input voltage		V_{REF} + 0.15		V_{CCIO} + 0.24	V
V_{IL} (AC)	Low-level AC input voltage		–0.24		V_{REF} – 0.15	V

Table 4–44. 1.5-V HSTL Class I and II Differential Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	I/O supply voltage		1.425	1.5	1.575	V
V_{DIF} (DC)	DC input differential voltage		0.2			V
V_{CM} (DC)	DC common mode input voltage		0.68		0.9	V
V_{DIF} (AC)	AC differential input voltage		0.4			V
V_{OX} (AC)	AC differential cross point voltage		0.68		0.9	V

Table 4–45. 1.8-V HSTL Class I Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		1.71	1.80	1.89	V
V_{REF}	Input reference voltage		0.85	0.90	0.95	V
V_{TT}	Termination voltage		0.85	0.90	0.95	V
V_{IH} (DC)	DC high-level input voltage		V_{REF} + 0.1			V
V_{IL} (DC)	DC low-level input voltage		–0.3		V_{REF} – 0.1	V
V_{IH} (AC)	AC high-level input voltage		V_{REF} + 0.2			V
V_{IL} (AC)	AC low-level input voltage				V_{REF} – 0.2	V
V_{OH}	High-level output voltage	I_{OH} = 8 mA *(1)*	V_{CCIO} – 0.4			V
V_{OL}	Low-level output voltage	I_{OH} = –8 mA *(1)*			0.4	V

Note to Table 4–45:

(1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II GX Architecture* chapter in volume 1 of the *Stratix II GX Device Handbook*.

Bus Hold Specifications

Table 4–48 shows the Stratix II GX device family bus hold specifications.

Table 4–48. Bus Hold Parameters

Parameter	Conditions	V_{CCIO} Level										Unit
		1.2 V		1.5 V		1.8 V		2.5 V		3.3 V		
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Low sustaining current	$V_{IN} > V_{IL}$ (maximum)	22.5		25		30		50		70		µA
High sustaining current	$V_{IN} < V_{IH}$ (minimum)	–22.5		–25		–30		–50		–70		µA
Low overdrive current	$0 V < V_{IN} < V_{CCIO}$		120		160		200		300		500	µA
High overdrive current	$0 V < V_{IN} < V_{CCIO}$		–120		–160		–200		–300		–500	µA
Bus-hold trip point		0.45	0.95	0.5	1.0	0.68	1.07	0.7	1.7	0.8	2.0	V

On-Chip Termination Specifications

Tables 4–49 and 4–50 define the specification for internal termination resistance tolerance when using series or differential on-chip termination.

Table 4–49. On-Chip Termination Specification for Top and Bottom I/O Banks (Part 1 of 2) *Notes (1), (2)*

Symbol	Description	Conditions	Resistance Tolerance		
			Commercial Max	Industrial Max	Unit
25-Ω R_S 3.3/2.5	Internal series termination with calibration (25-Ω setting)	V_{CCIO} = 3.3/2.5 V	±5	±10	%
	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 3.3/2.5 V	±30	±30	%
50-Ω R_S 3.3/2.5	Internal series termination with calibration (50-Ω setting)	V_{CCIO} = 3.3/2.5 V	±5	±10	%
	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 3.3/2.5 V	±30	± 30	%

Table 4–77. EP2SGX130 Column Pins Regional Clock Timing Parameters

Parameter	Fast Corner		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Units
	Industrial	Commercial				
t_{CIN}	1.815	1.834	3.218	3.417	4.087	ns
t_{COUT}	1.650	1.669	3.218	3.417	4.087	ns
t_{PLLCIN}	0.116	0.134	0.349	0.364	0.426	ns
$t_{PLLCOUT}$	-0.049	-0.031	0.361	0.378	0.444	ns

Table 4–78. EP2SGX130 Row Pins Regional Clock Timing Parameters

Parameter	Fast Corner		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Units
	Industrial	Commercial				
t_{CIN}	1.544	1.560	3.195	3.395	4.060	ns
t_{COUT}	1.549	1.565	3.195	3.395	4.060	ns
t_{PLLCIN}	-0.149	-0.132	0.34	0.356	0.417	ns
$t_{PLLCOUT}$	-0.144	-0.127	0.342	0.356	0.417	ns

Clock Network Skew Adders

The Quartus II software models skew within dedicated clock networks such as global and regional clocks. Therefore, the intra-clock network skew adder is not specified. Table 4–79 specifies the intra-clock skew between any two clock networks driving any registers in the Stratix II GX device.

Table 4–79. Clock Network Specifications (Part 1 of 2)

Name	Description	Min	Typ	Max	Unit
Clock skew adder EP2SGX30 *(1)*	Inter-clock network, same side			±50	ps
	Inter-clock network, entire chip			±100	ps
Clock skew adder EP2SGX60 *(1)*	Inter-clock network, same side			±50	ps
	Inter-clock network, entire chip			±100	ps
Clock skew adder EP2SGX90 *(1)*	Inter-clock network, same side			±55	ps
	Inter-clock network, entire chip			±110	ps

Table 4–85. Stratix II GX I/O Input Delay for Row Pins (Part 2 of 3)

I/O Standard	Parameter	Fast Corner Industrial/ Commercial	-3 Speed Grade *(2)*	-3 Speed Grade *(3)*	-4 Speed Grade	-5 Speed Grade	Unit
LVCMOS	t_{PI}	749	1287	1350	1435	1723	ps
	t_{PCOUT}	410	760	798	848	1018	ps
SSTL-2 Class I	t_{PI}	573	879	921	980	1176	ps
	t_{PCOUT}	234	352	369	393	471	ps
SSTL-2 Class II	t_{PI}	573	879	921	980	1176	ps
	t_{PCOUT}	234	352	369	393	471	ps
SSTL-18 Class I	t_{PI}	605	960	1006	1070	1285	ps
	t_{PCOUT}	266	433	454	483	580	ps
SSTL-18 Class II	t_{PI}	605	960	1006	1070	1285	ps
	t_{PCOUT}	266	433	454	483	580	ps
1.5-V HSTL Class I	t_{PI}	631	1056	1107	1177	1413	ps
	t_{PCOUT}	292	529	555	590	708	ps
1.5-V HSTL Class II	t_{PI}	631	1056	1107	1177	1413	ps
	t_{PCOUT}	292	529	555	590	708	ps
1.8-V HSTL Class I	t_{PI}	605	960	1006	1070	1285	ps
	t_{PCOUT}	266	433	454	483	580	ps
1.8-V HSTL Class II	t_{PI}	605	960	1006	1070	1285	ps
	t_{PCOUT}	266	433	454	483	580	ps
PCI	t_{PI}	830	1498	1571	1671	2006	ps
	t_{PCOUT}	491	971	1019	1084	1301	ps
PCI-X	t_{PI}	830	1498	1571	1671	2006	ps
	t_{PCOUT}	491	971	1019	1084	1301	ps
LVDS *(1)*	t_{PI}	540	948	994	1057	1269	ps
	t_{PCOUT}	201	421	442	470	564	ps
HyperTransport	t_{PI}	540	948	994	1057	1269	ps
	t_{PCOUT}	201	421	442	470	564	ps
Differential SSTL-2 Class I	t_{PI}	573	879	921	980	1176	ps
	t_{PCOUT}	234	352	369	393	471	ps
Differential SSTL-2 Class II	t_{PI}	573	879	921	980	1176	ps
	t_{PCOUT}	234	352	369	393	471	ps

Therefore, the DCD percentage for the output clock is from 48.4% to 51.6%.

Table 4–101. Maximum DCD for DDIO Output on Row I/O Pins Without PLL in the Clock Path for -4 and -5 Devices *Note (1)*

Maximum DCD (ps) for Row DDIO Output I/O Standard	Input I/O Standard (No PLL in the Clock Path)					Unit
	TTL/CMOS		SSTL-2	SSTL/HSTL	LVDS	
	3.3/2.5V	1.8/1.5V	2.5V	1.8/1.5V	3.3V	
3.3-V LVTTL	440	495	170	160	105	ps
3.3-V LVCMOS	390	450	120	110	75	ps
2.5 V	375	430	105	95	90	ps
1.8 V	325	385	90	100	135	ps
1.5-V LVCMOS	430	490	160	155	100	ps
SSTL-2 Class I	355	410	85	75	85	ps
SSTL-2 Class II	350	405	80	70	90	ps
SSTL-18 Class I	335	390	65	65	105	ps
1.8-V HSTL Class I	330	385	60	70	110	ps
1.5-V HSTL Class I	330	390	60	70	105	ps
LVDS	180	180	180	180	180	ps

(1) Table 4–101 assumes the input clock has zero DCD.

Table 4–102. Maximum DCD for DDIO Output on Column I/O Pins Without PLL in the Clock Path for -3 Devices (Part 1 of 2) *Note (1)*

Maximum DCD (ps) for DDIO Column Output I/O Standard	Input IO Standard (No PLL in the Clock Path)					Unit
	TTL/CMOS		SSTL-2	SSTL/HSTL	HSTL12	
	3.3/2.5V	1.8/1.5V	2.5V	1.8/1.5V	1.2V	
3.3-V LVTTL	260	380	145	145	145	ps
3.3-V LVCMOS	210	330	100	100	100	ps
2.5 V	195	315	85	85	85	ps
1.8 V	150	265	85	85	85	ps
1.5-V LVCMOS	255	370	140	140	140	ps
SSTL-2 Class I	175	295	65	65	65	ps
SSTL-2 Class II	170	290	60	60	60	ps
SSTL-18 Class I	155	275	55	50	50	ps

Table 4–108 shows the high-speed I/O timing specifications for -4 speed grade Stratix II GX devices.

Table 4–108. High-Speed I/O Specifications for -4 Speed Grade *Notes (1), (2)*

Symbol	Conditions			-4 Speed Grade			Unit
				Min	Typ	Max	
$f_{IN} = f_{HSDR} / W$	W = 2 to 32 (LVDS, HyperTransport technology) *(3)*			16		520	MHz
	W = 1 (SERDES bypass, LVDS only)			16		500	MHz
	W = 1 (SERDES used, LVDS only)			150		717	MHz
f_{HSDR} (data rate)	J = 4 to 10 (LVDS, HyperTransport technology)			150		1,040	Mbps
	J = 2 (LVDS, HyperTransport technology)			*(4)*		760	Mbps
	J = 1 (LVDS only)			*(4)*		500	Mbps
$f_{HSDRDPA}$ (DPA data rate)	J = 4 to 10 (LVDS, HyperTransport technology)			150		1,040	Mbps
TCCS	All differential standards			-		200	ps
SW	All differential standards			330		-	ps
Output jitter						190	ps
Output t_{RISE}	All differential I/O standards					160	ps
Output t_{FALL}	All differential I/O standards					180	ps
t_{DUTY}				45	50	55	%
DPA run length						6,400	UI
DPA jitter tolerance	Data channel peak-to-peak jitter			0.44			UI
DPA lock time							Number of repetitions
	SPI-4	0000000000 1111111111	10%	256			
	Parallel Rapid I/O	00001111	25%	256			
		10010000	50%	256			
	Miscellaneous	10101010	100%	256			
		01010101		256			

(1) When J = 4 to 10, the SERDES block is used.
(2) When J = 1 or 2, the SERDES block is bypassed.
(3) The input clock frequency and the W factor must satisfy the following fast PLL VCO specification: 150 ≤nput clock frequency × W ≤1,040.
(4) The minimum specification is dependent on the clock source (fast PLL, enhanced PLL, clock pin, and so on) and the clock routing resource (global, regional, or local) utilized. The I/O differential buffer and input register do not have a minimum toggle rate.

PLL Timing Specifications

Tables 4–110 and 4–111 describe the Stratix II GX PLL specifications when operating in both the commercial junction temperature range (0 to 85 C) and the industrial junction temperature range (–40 to 100 C), except for the clock switchover and phase-shift stepping features. These two features are only supported from the 0 to 100 C junction temperature range.

Table 4–110. Enhanced PLL Specifications (Part 1 of 2)

Name	Description	Min	Typ	Max	Unit
f_{IN}	Input clock frequency	4		500	MHz
f_{INPFD}	Input frequency to the PFD	4		420	MHz
f_{INDUTY}	Input clock duty cycle	40		60	%
f_{ENDUTY}	External feedback input clock duty cycle	40		60	%
$t_{INJITTER}$	Input or external feedback clock input jitter tolerance in terms of period jitter. Bandwidth ≤0.85 MHz		0.5		ns (peak-to-peak)
	Input or external feedback clock input jitter tolerance in terms of period jitter. Bandwidth > 0.85 MHz		1.0		ns (peak-to-peak)
$t_{OUTJITTER}$	Dedicated clock output period jitter			250 ps for ≥ 100 MHz outclk 25 mUI for < 100 MHz outclk	ps or mUI (p-p)
t_{FCOMP}	External feedback compensation time			10	ns
f_{OUT}	Output frequency for internal global or regional clock	1.5 *(2)*		550	MHz
$f_{OUTDUTY}$	Duty cycle for external clock output	45	50	55	%
$f_{SCANCLK}$	Scanclk frequency			100	MHz
$t_{CONFIGEPLL}$	Time required to reconfigure scan chains for EPLLs		$174/f_{SCANCLK}$		ns
f_{OUT_EXT}	PLL external clock output frequency	1.5 *(2)*		*(1)*	MHz
t_{LOCK}	Time required for the PLL to lock from the time it is enabled or the end of device configuration		0.03	1	ms
t_{DLOCK}	Time required for the PLL to lock dynamically after automatic clock switchover between two identical clock frequencies			1	ms
$f_{SWITCHOVER}$	Frequency range where the clock switchover performs properly	1.5	1	500	MHz
f_{CLBW}	PLL closed-loop bandwidth	0.13	1.2	16.9	MHz